

Search Notes

Application/Control No.

10/524,182

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under
Reexamination

REDMAN-WHITE ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	281	8/29/2006	HN
330	284-285	8/29/2006	HN
330	144-145	8/29/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	8/27/2006	HN